

RADIATION HARDENED
NPN POWER SILICON TRANSISTOR
Qualified per MIL-PRF-19500/544

Qualified Levels:
 JANSM, JANSJ,
 JANSK, JANSL,
 JANSR, JANSF

DESCRIPTION

These RHA level 2N5152U3 and 2N5154U3 silicon transistor devices are military Radiation Hardness Assurance qualified up to a JANSF level for high-reliability applications. Microsemi also offers numerous other products to meet higher and lower power voltage regulation applications.

Important: For the latest information, visit our website <http://www.microsemi.com>.

FEATURES

- JEDEC registered 2N5152 and 2N5154.
- JANS RHA qualifications are available per MIL-PRF-19500/544.

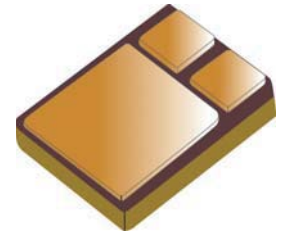
APPLICATIONS / BENEFITS

- High frequency operation.
- Lightweight.
- High-speed power-switching applications.
- High-reliability applications.

MAXIMUM RATINGS


Parameters/Test Conditions	Symbol	Value	Unit
Junction and Storage Temperature	T_J and T_{STG}	-65 to +200	°C
Thermal Resistance Junction-to-Ambient	$R_{\theta JA}$	175	°C/W
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	10	°C/W
Reverse Pulse Energy ⁽¹⁾		15	mJ
Collector Current (dc)	I_C	2	A
Collector to base voltage (static), emitter open	V_{CBO}	100	V
Collector to emitter voltage (static) base open	V_{CEO}	80	V
Emitter to base voltage (static) collector open	V_{EBO}	5.5	V
Steady-State Power Dissipation @ $T_A = +25\text{ °C}$	P_D	1	W
Steady-State Power Dissipation @ $T_C = +25\text{ °C}$	P_D	10	W


Notes: 1. This rating is based on the capability of the transistors to operate safely in the unclamped inductive load energy test circuit.



**U3 (SMD-0.5)
Package**

Also available in:

 **TO-5 Package**
 (long-leaded)
 JANS_2N5152L &
 JANS_2N5154L

 **TO-39 Package**
 (leaded)
 JANS_2N5152 &
 JANS_2N5154

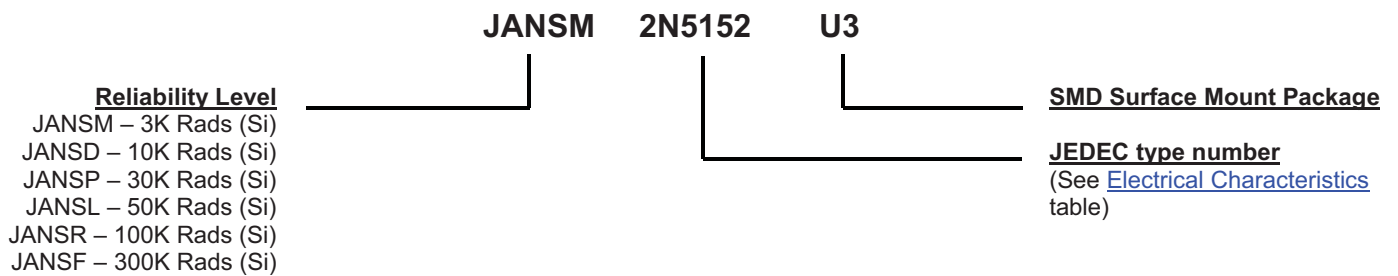
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MECHANICAL and PACKAGING

- CASE: Ceramic and gold over nickel plated steel.
- TERMINALS: Gold over nickel plated tungsten/copper.
- MARKING: Part number, date code, A = anode.
- POLARITY: See [schematic](#) on last page.
- WEIGHT: 0.9 grams.
- See [Package Dimensions](#) on last page.

PART NOMENCLATURE

SYMBOLS & DEFINITIONS

Symbol	Definition
C_{obo}	Common-base open-circuit output capacitance.
I_{CEO}	Collector cutoff current, base open.
I_{CEX}	Collector cutoff current, circuit between base and emitter.
I_{EBO}	Emitter cutoff current, collector open.
h_{FE}	Common-emitter static forward current transfer ratio.
V_{CEO}	Collector-emitter voltage, base open.
V_{CBO}	Collector-emitter voltage, emitter open.
V_{EBO}	Emitter-base voltage, collector open.

ELECTRICAL CHARACTERISTICS @ $T_A = +25^\circ\text{C}$ unless otherwise noted.
OFF CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Collector-Emitter Breakdown Voltage $I_C = 100\text{ mA}, I_B = 0$	$V_{(BR)CEO}$	80		V
Emitter-Base Cutoff Current $V_{EB} = 4.0\text{ V}, I_C = 0$ $V_{EB} = 5.5\text{ V}, I_C = 0$	I_{EBO}		1.0 1.0	μA mA
Collector-Emitter Cutoff Current $V_{CE} = 60\text{ V}, V_{BE} = 0$ $V_{CE} = 100\text{ V}, V_{BE} = 0$	I_{CES}		1.0 1.0	μA mA
Collector-Emitter Cutoff Current $V_{CE} = 40\text{ V}, I_B = 0$	I_{CEO}		50	μA

ON CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Forward-Current Transfer Ratio $I_C = 50\text{ mA}, V_{CE} = 5\text{ V}$	h_{FE}	20	--	
2N5152U3		50	--	
$I_C = 2.5\text{ A}, V_{CE} = 5\text{ V}$		30	90	
2N5154U3		70	200	
$I_C = 5\text{ A}, V_{CE} = 5\text{ V}$		20	--	
2N5154U3		40	--	
Collector-Emitter Saturation Voltage $I_C = 2.5\text{ A}, I_B = 250\text{ mA}$ $I_C = 5.0\text{ A}, I_B = 500\text{ mA}$	$V_{CE(sat)}$		0.75 1.5	V
Base-Emitter Voltage Non-Saturation $I_C = 2.5\text{ A}, V_{CE} = 5\text{ V}$	V_{BE}		1.45	V
Base-Emitter Saturation Voltage $I_C = 2.5\text{ A}, I_B = 250\text{ mA}$ $I_C = 5.0\text{ A}, I_B = 500\text{ mA}$	$V_{BE(sat)}$		1.45 2.2	V

DYNAMIC CHARACTERISTICS

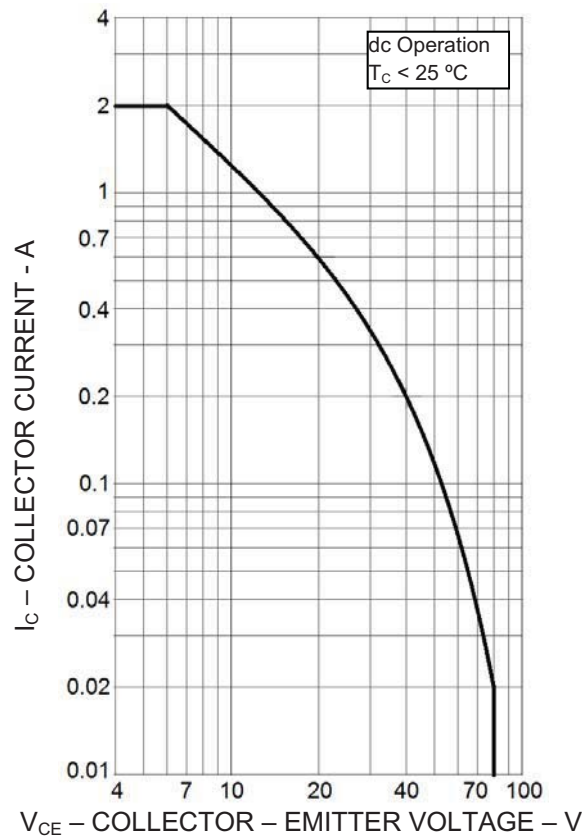
Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Magnitude of Common Emitter Small-Signal Short-Circuit Forward Current Transfer Ratio 2N5152U3 2N5154U3 $I_C = 500\text{ mA}, V_{CE} = 5\text{ V}, f = 10\text{ MHz}$	$ h_{fe} $	6 7		
Small-signal short Circuit Forward-Current Transfer Ratio 2N5152U3 2N5154U3 $I_C = 100\text{ mA}, V_{CE} = 5\text{ V}, f = 1\text{ KHz}$	h_{fe}	20 50		
Output Capacitance $V_{CB} = 10\text{ V}, I_E = 0, f = 1.0\text{ MHz}$	C_{obo}		250	pF

ELECTRICAL CHARACTERISTICS @ $T_A = +25\text{ }^\circ\text{C}$ unless otherwise noted. (continued)
SWITCHING CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Turn-On Time $I_C = 5\text{ A}$, $I_{B1} = 500\text{ mA}$	t_{on}		0.5	μs
Turn-Off Time $R_L = 6\Omega$	t_{off}		1.5	μs
Storage Time $I_{B2} = -500\text{ mA}$	t_s		1.4	μs
Fall Time $V_{BE(OFF)} = 3.7\text{ V}$	t_f		0.5	μs

SAFE OPERATING AREA (See SOA graph below and [MIL-STD-750, method 3053](#))

DC Tests
 $T_C = +25\text{ }^\circ\text{C}$, $t_p = 1.0\text{ s}$, 1 Cycle

Test 1
 $V_{CE} = 5.0\text{ V}$, $I_C = 2.0\text{ A}$
Test 2
 $V_{CE} = 32\text{ V}$, $I_C = 310\text{ mA}$
Test 3
 $V_{CE} = 80\text{ V}$, $I_C = 12.5\text{ mA}$

Maximum Safe Operating Area

ELECTRICAL CHARACTERISTICS @ $T_A = +25\text{ }^\circ\text{C}$, unless otherwise noted (continued)
POST RADIATION ELECTRICAL CHARACTERISTICS

Parameters / Test Conditions	Symbol	Min.	Max.	Unit
Collector to Emitter Cutoff Current $V_{CE} = 40\text{ V}$	I_{CEO}		100	μA
Emitter to Base Cutoff Current $V_{EB} = 4\text{ V}$	I_{EBO}		2.0	μA
Breakdown Voltage, Collector to Emitter $I_C = 100\text{ mA}$	$V_{(BR)CEO}$	80		V
Collector to Emitter Cutoff Current $V_{CE} = 60\text{ V}$	I_{CES}		2.0	μA
Emitter to Base Cutoff Current $V_{EB} = 5.5\text{ V}$	I_{EBO}		2.0	mA
Forward-Current Transfer Ratio ⁽¹⁾ $I_C = 50\text{ mA}$, $V_{CE} = 5\text{ V}$				
	2N5152U3	[10]		
	2N5154U3	[25]		
$I_C = 2.5\text{ A}$, $V_{CE} = 5\text{ V}$				
	2N5152U3	[15]	90	
	2N5154U3	[35]	200	
$I_C = 5\text{ A}$ pulsed, $V_{CE} = 5\text{ V}$				
	2N5152U3	[10]		
	2N5154U3	[20]		
Base to Emitter voltage (non-saturated) $V_{CE} = 5\text{ V}$, $I_C = 2.5\text{ A}$, pulsed	V_{BE}		1.45	V
Collector-Emitter Saturation Voltage $I_C = 2.5\text{ mA}$, $I_B = 250\text{ mA}$, pulsed $I_C = 500\text{ mA}$, $I_B = 500\text{ mA}$, pulsed	$V_{CE(sat)}$		0.86 1.73	V
Base-Emitter Saturation Voltage $I_C = 2.5\text{ A}$, $I_B = 250\text{ mA}$, pulsed $I_C = 5\text{ A}$, $I_B = 500\text{ mA}$, pulsed	$V_{BE(sat)}$		1.67 2.53	V

- (1) See method 1019 of MIL-STD-750 for how to determine $[h_{FE}]$ by first calculating the delta ($1/h_{FE}$) from the pre- and post-radiation h_{FE} . Notice the $[h_{FE}]$ is not the same as h_{FE} and cannot be measured directly. The $[h_{FE}]$ value can never exceed the pre-radiation minimum h_{FE} that it is based upon.

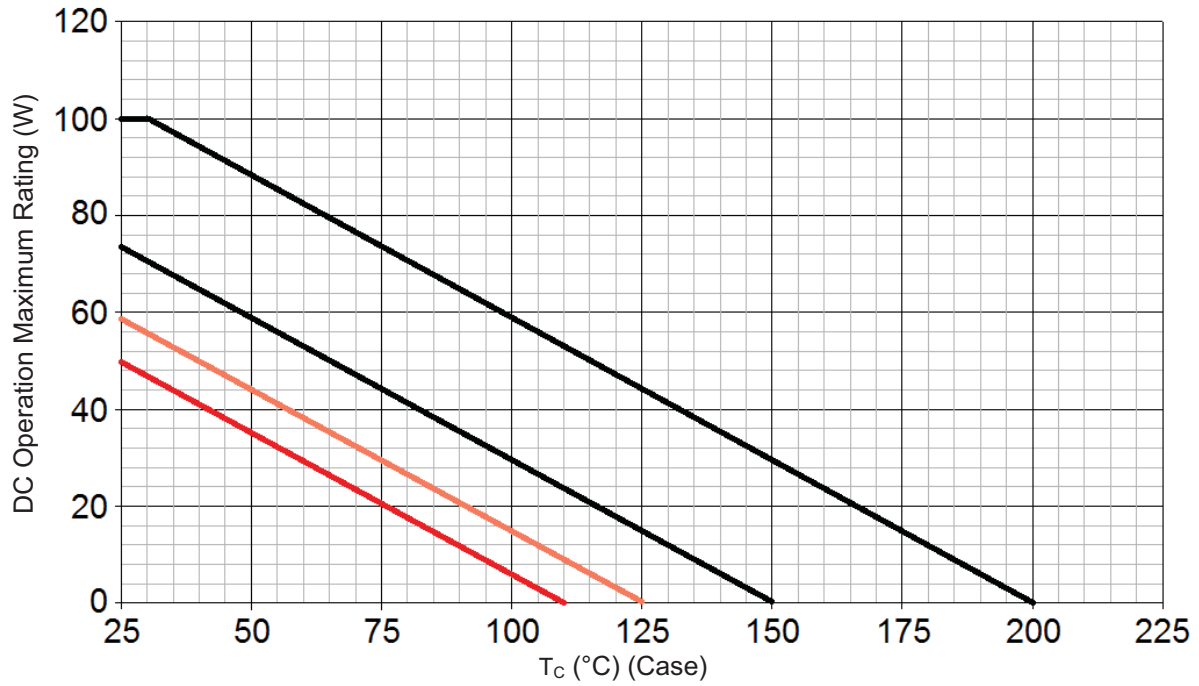
GRAPHS


FIGURE 1
Temperature-Power Derating Curve

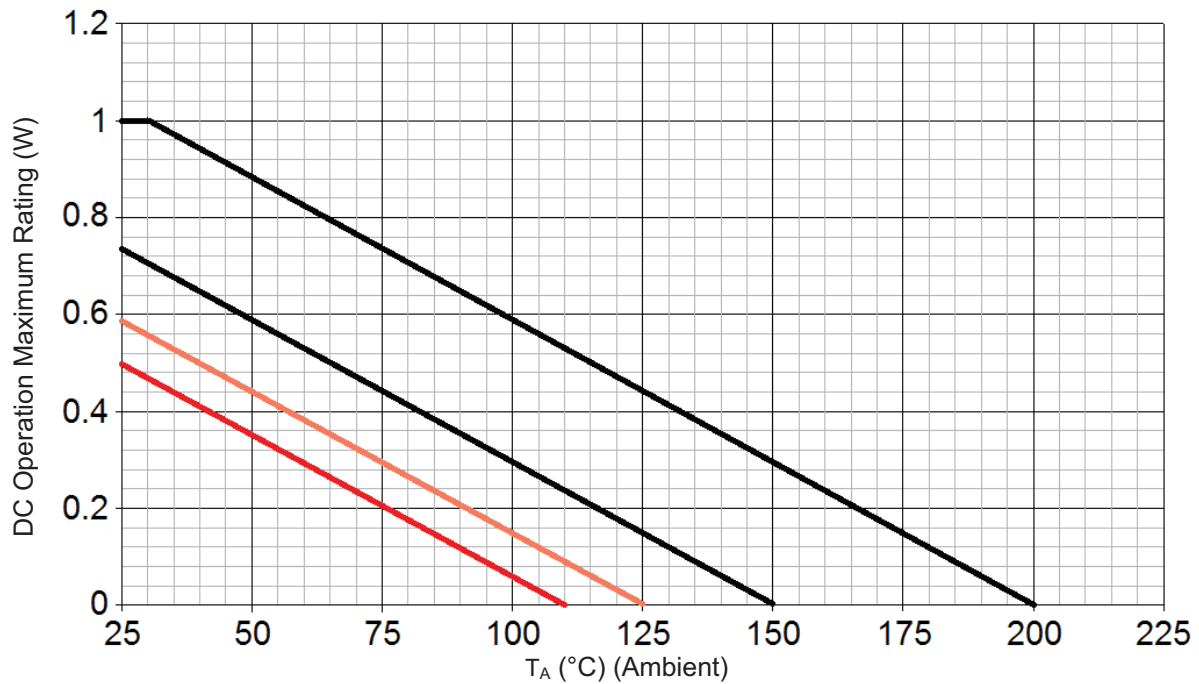


FIGURE 2
Temperature-Power Derating Curve

GRAPHS (continued)

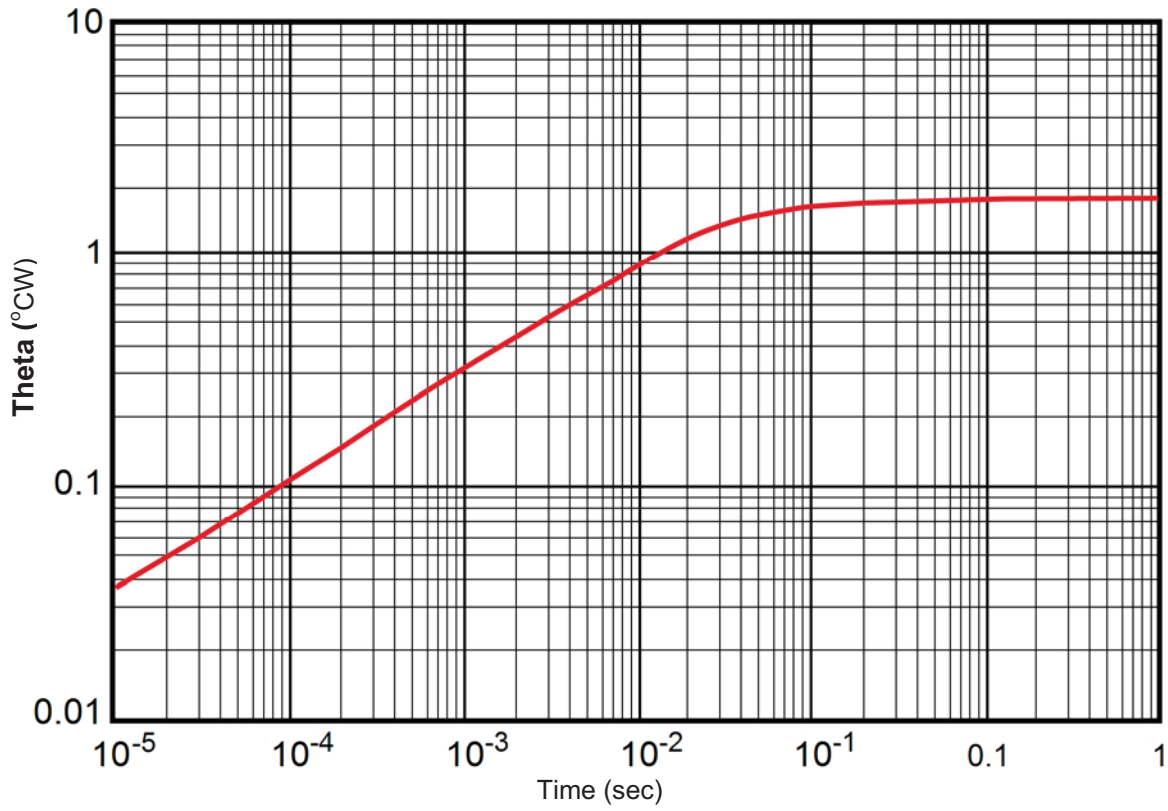


FIGURE 3
Maximum Thermal Impedance ($R_{\theta JC}$)